Improving Signal-to-Noise by Identifying Sources of Noise in Mass Spectrometer Systems

Kevin Kuchta
Extrel CMS 575 Epsilon Drive, Pittsburgh, PA 15238

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Introduction:

With increasing demands on the sensitivity of mass spectrometers, signal-to-noise ratios are of greater importance. Increasing signal strength may not help if noise levels also increase. Therefore, it is of the utmost importance to reduce noise. To do so, one must correctly identify its source. Noise may be defined as “anything in the spectrum that is unwanted.” However, this would include everything from gaseous background peaks to an unexpected resultant spectrum to a conductor sporadically shorting to another conductor or to ground.

To locate the source of the noise, one must first characterize it. Is the noise completely random, or is there some pattern to it? What parameters affect the noise?

We have shown ways to improve signal-to-noise in previous papers. One could configure the analyzing quad and detector off-axis, as shown in figure 1, so that neutrals from the beam do not add noise to the detected signal or filter out any on-axis stray electrons or photons with an axial energy filter as shown in figure 2. This on-axis design resulted in an increased partial pressure detection.

The following tuning parameters, figure 3, are an example of a way to increase signal on a Quadrupole mass spectrometer when using an EI ionizer. These tuning changes resulted in a signal increase of 5.6x. However, the increased emission also resulted in an increase in noise. Without the use of an energy filter, as shown earlier, the overall signal/noise increase did not prove beneficial.
Background Information:

It is apparent that, unless some sort of filter is utilized, that noise must be decreased. The origin of a noise can often times be difficult to identify. The types of noise often seen in mass spectrometer systems are electrical and/or mechanical. Sometimes, complex forms of these noise spectra can be present in a spectrum. As we all know, mass spectrometers operate in vacuum chambers that use pumps to generate said vacuum. This fact should make it easy to identify any vibrational noise frequency. However, mass spectrometers are also controlled by electronics. Electronics often use switching DC power supplies that switch at specific frequencies. Is it possible to differentiate these different sources of noise?

Before we can discuss specifics, let’s look at some basic frequency characteristics:

- Constructive interference occurs when the crests of two waves line up. This gives an additive result with the resultant peak having a higher amplitude.

- Destructive interference occurs when the crest of one wave lines up with the trough of another wave. This reduces the amplitude of the resultant wave.

Another phenomenon that can make noise and frequency analysis complicated is harmonic representation. As shown below, the fundamental frequency can be seen at 1, 2, 3,...,x. Although the amplitude can vary for harmonics, the following example is shown with the first and second harmonic multiplied by 2 and 3, respectively.

Harmonics Example:

To define a wave function, we must first define our variables.

\[ \omega_0 := 1 \quad \omega_1 := 2 \quad \phi_0 := 1 \quad \phi_1 := 0.5 \]

Now we can define the function.

\[ f(t) := \sin(\omega_0 t + \phi_0) \]
\[ f_1(t) := \sin(\omega_1 t + \phi_1) \]
\[ z(t) := f(t) + f_1(t) \]

Experimental Data:

The following data are shown as extreme cases to exemplify the types of noise seen in typical mass spectrometer systems. The noise spectra were recorded on a digital oscilloscope and deconvoluted by the scopemeter’s own software using a Fast Fourier Transform (FFT) algorithm.

Several common situations were modeled. Roughing pumps can “walk” on the laboratory floor while operating. Often, the pump can walk right into the mass spectrometer’s chamber rack, thus slightly vibrating the rack at the frequency at which the pump operates. This causes the in-vacuum, unshielded leads to vibrate. When unshielded leads vibrate, they can induce small voltages into themselves or neighboring conductors. The amplitude of the induced voltage can vary due to the strength of the vibration, the rigidity of the conductor and the environment in which it operates or its proximity to other electric fields, including ground.

Figures 6 and 7 on the next page show the result of a diaphragm roughing pump vibrating against the chamber rack. The pump rotates at 1200 rpm, or 20 Hz. This frequency can
be seen in the FFT spectrum. However, it also created a beat pattern of a much higher amplitude seen at a higher frequency than the fundamental frequency.

![Figure 6]

Vibrational spectrum with rotary vane roughing pump.

Figures 8 and 9 show the result of a rotary vane roughing pump vibrating against the chamber rack. The pump rotates at very close to the same speed. However, its amplitude is much lower due to the lower intensity of the vibration.

![Figure 7]

Vibrational spectrum with diaphragm roughing pump.

Figures 10 and 11 show an example of both a rotary vane pump and a turbo molecular pump. Notice in the wave form that both frequencies can be seen.

![Figure 10]

Deconvolved spectrum showing two prominent frequencies, roughing pump and an harmonic of the turbo-molecular pump.

Figure 11

It is important to note that in the previous examples, the more intense amplitudes are seen at a much higher frequencies than the pumps’ operating rotational frequencies. This is most often the case. The constructive interference of frequencies from roughing pump and turbo-molecular pumps produces a frequency higher than the fundamental frequency of the roughing pump and lower than the rotational frequency of the TMP. This beat pattern can be deceiving and make it difficult to identify the source of the noise.

![Figure 11]
Electronic frequencies, such as those seen from switching DC power supplies, present themselves less sinusoidal than vibrational noises. The noise spectrum shown in figures 12 and 13 is that of a switching DC supply. Notice that its amplitude is much lower than that of vibrational noise sources. Also, notice the harmonics seen in the FFT spectrum.

The easiest way to tell if the source of a noise is mechanical or electrical is the “tap test.” Tapping on the chamber with a small mallet or the handle of a screwdriver while observing can show, sometimes very obviously, if the noise source is mechanical.

Figure 14 shows a noise spectrum taken during a tap test. Notice the “ringing” of the noise. Ringing is a term used to describe the prolonged decay time of a frequency as it dissipates.

Quadrupole mass spectrometers use RF voltage to filter ions. If in-vacuum conductors are too close to the RF leads, it can be seen in the spectrum. In the example is shown in figure 15. Notice how the noise increases as the RF voltage increases, that is with higher mass. Again, this is an extreme case, but exemplifies the condition.
Various lengths of in-vacuum leads were tested. The previous spectra were taken with “standard” or “off the shelf” continuous dynode electron multipliers in analog mode. In figures 16 and 17 the spectrum was obtained with an electron multiplier mounted directly to a flange and used very rigid, glass-coated in-vacuum leads.

Conclusion:

Increasing signal does not necessarily increase signal to noise. It is more important to identify the source of the noise. Sources of noise in mass spectrometers can be varied and very difficult to identify. One must take an holistic approach to analyzing the amplitude, frequency and even shape of the noise spectrum.

Mechanical noise frequencies produce more sinusoidal patterns. Multiple mechanical sources often produce beat patterns with each other resulting in a frequency faster than one and slower than the other parent frequency. Conversely, electronic noise frequencies tend to take on a more digital or square wave pattern. Electronic noise sources also often produce harmonics that can be seen at multiples of the fundamental frequency.

Since pumps and other sources of vibration may not be able to be eliminated, the affect they have on spectra may be minimized. Shortening in-vacuum leads and supporting them rigidly greatly reduced the affects of mechanical vibrations.

References: